

Agilent Dreamliner 2009 Onboard Demonstrations

This year's Dreamliner has a number of brand new things you've never seen before, and advanced setups that show what we achieve by designing our instruments to work together. For analog and digital challenges, come see what's possible!

New RF Handheld Analyzers/Testers

New Audio Analyzer: Demonstration will show the next generation capabilities of the U8903A, replacement for the 8903B with capabilities for digital audio formats as well.

New multi-channel baseband generator: Choose from 1) fading 2) interference/blocking test 3) MIMO

New Power Meter, Handheld DMM.

New High Performance & RF Microwave Test Accessories: New Switches, preamp. dividers

New Power Device Analyzer/Curve Tracer: Measure power devices at 20A and 3000V with the ease of a curve tracer and the convenience of a PC.

New Oscilloscopes: Two brand new families of scopes.

Infiniium 9000 Oscilloscope: A new family of high performance oscilloscopes

Series 1000 Oscilloscope: A new entry-level oscilloscope

Logic Analyzer applications: The 16900 mainframe logic analyzer showing applications for FPGA, SDRAM, and DDR. Our new 16962A module is the world's first and only logic analysis solution for all DDR including DDR3.

InfiniiVision MSO 7000, InfiniiVision 5000 scopes Our current mid-range mixed-signal and conventional scopes.

Vector signal generation and analysis: The latest instruments for complex signal generation and analysis. Choose from two sig gen demos and two spec an demos: 1) intermodulation distortion performance, 2) signal studio app, 3) matlab app, 4) VXA flex demod

Comprehensive Active-Device Test with PNA-X Network Analyzer: The world's most advanced network analyzer. PNA-X measures an amplifier's gain, gain compression, harmonics, IMD, and noise figure with one easy setup and without an external combiner or filters. A new calibration technique yields the industry's most accurate noise figure measurements.

Extending Microwave Performance to cover more Frequency Ranges and Bandwidths

Signal Analyzer applications: Choose from 1) EMC pre-compliance, 2) Vector signal analysis and digital demod

Satellite and Milcom applications: The set-up provides solutions to users active in Satellite and A&D Communications as well as for general purpose characterization of fast single shot and repetitive signals.

Basic RF instruments Simple, raw performance demo - shows that low cost sig gen has good AM mod and phase noise perf. Show that spec an has good DANL, FSK demod.

E5052B Signal Source Analyzer: An advanced "signal source" test will be demonstrated. Topics included are characterizing oscillator transient behaviors such as phase-hits, and clock jitter analysis to estimate BER.

E5071C 20GHz ENA-C Network Analyzer: This demo shows the 4.5GHz/8.5GHz/20GHz ENA Network Analyzer's basic measurement capabilities as the complete replacement of the 8753/19/20 Network Analyzers.

J7211B Attenuation Control Unit : J7211B offers an integrated solution which provides up to 121 dB attenuation with 1 dB steps. It is designed for R&D and mfg engineers in wireless communication, A/D and electronic component industries.

Bench in Your Bag: Show portability and ease of use of USB modular instruments

Characterization of wireline transmitters and receivers: 86100C & 86108A characterizes transmitter signals most accurately through a very low noise floor. N4903B High Performance BERT is an ideal tool for jitter tolerance testing. The integrated design of both instruments ensures maximum margins

PCI EXPRESS Jammer, HDMI, RXD Solution for RXD: The DigRF demo showcases Agilent's industry leading protocol analyzer and interactive exerciser system for mobile handset customers

R&D GP Instrument Demo: This demo showcases Agilent's GP/BI portfolio and how these products can seamlessly operate together in an R&D bench application to produce valuable results.

DC Power Analysis: Characterizing run time of a battery powered device: The N6705B is the fastest easiest way to characterize a battery powered device. Testing can be done from the front panel and does not require a computer.

Electronic Functional Test (EFT): This demo showcases DAQ (switching/digitizer) products in an automated application using an A/D-oriented DUT.

New Scanning Microwave Microscopy (SMM Mode) with Atomic Force Microscope:

You may not need one of these, but it's very cool to see. You can count atoms with this thing! SMM mode combines the electrical measurement capabilities of an Agilent PNA with the high spatial resolution of an AFM. SMM mode enables quantitative, calibrated capacitance and dopant density and complex impedance measurements.